Progress in Surface Science

An International Review Journal

EDITOR-IN-CHIEF: Professor Sydney G. Davison

AUTHOR AND SUBJECT INDEX

Volume 52, 1996

PERGAMON

Progress in Surface Science

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Published Monthly. *Annual Institutional Subscription Rates* (1996): North, Central and South America, U.S.$835.00, Rest of World £525.00. Sterling prices exclude VAT. Non-Vat registered customers in the European Community will be charged the appropriate VAT in addition to the price listed. Prices include postage and insurance and are subject to change without notice.

PII: S0079-6816(98)00005-7

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